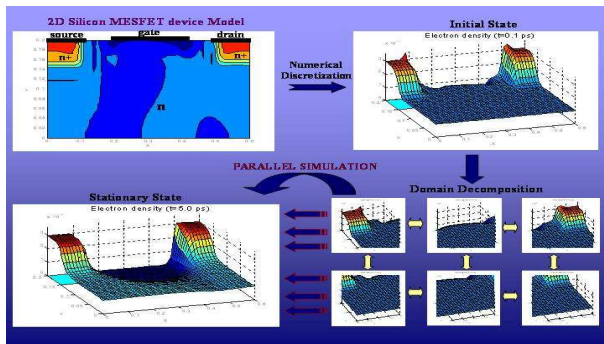


Simulación Paralela Determinista de dispositivos semiconductores 2D basada en esquemas WENO-Boltzmann

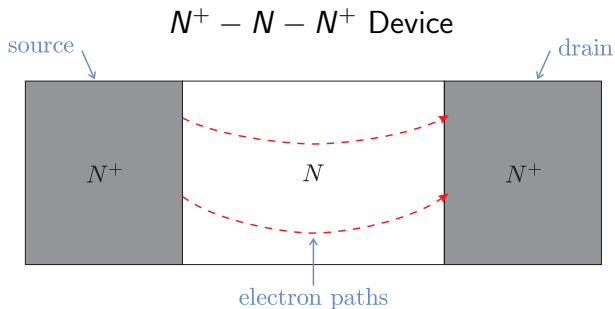
J. M. Mantas Ruiz, R. J. García
Depto. Lenguajes y Sistemas Inf.
Univ. Granada

M.J. Cáceres
Depto. Matemática Aplicada.
Univ. Granada



1. Introduction
2. WENO-Boltzmann scheme
3. Representation of device information
4. Numerical methods
5. Parallel algorithm
6. Experimental results
7. Further work

Introduction



Cross-section of a $N^+ - N - N^+$ device

Semiclassical Approximation. Boltzmann-Poisson System

- ▶ **Boltzmann Transport Equation for semiconductors:**

$$\frac{\partial f}{\partial t} + \frac{1}{\hbar} \nabla_k \varepsilon \cdot \nabla_x f - \frac{e}{\hbar} \mathbf{E} \cdot \nabla_k f = Q(f)$$

- ▶ f is the electron probability density function in phase space (x, k) at each time t .
- ▶ **Poisson Equation:** To compute Electric field $\mathbf{E} = -\nabla_x V$, the potential V satisfies:

$$\nabla_x [\epsilon_r(x) \nabla_x V] = -q [\rho(t, x) - N_D(x)],$$

$\rho(t, x)$ = electron density, $N_D(x)$ is the doping profile and $\epsilon_r(x)$ is the dielectric constant.

WENO-Boltzmann scheme (*Carrillo et. al. 2003*)

Adimensionalization + pseudospherical change of variable for k

$$\Phi(t, x, y, w, \mu, \phi) = s(w)f(t, x, y, w, \mu, \phi).$$

Adimensional Boltzmann Eq. in 2D physical space

$$\frac{\partial \Phi}{\partial t} + \frac{\partial}{\partial x}(a_1 \Phi) + \frac{\partial}{\partial y}(a_2 \Phi) + \frac{\partial}{\partial w}(a_3 \Phi) + \frac{\partial}{\partial \mu}(a_4 \Phi) + \frac{\partial}{\partial \phi}(a_5 \Phi) = s(w)C(\Phi)$$

a_3, a_4, a_5 depends on $\mathbf{E} = [E_x, E_y] = [\frac{\partial V}{\partial x}, \frac{\partial V}{\partial y}]$.

2D Poisson Equation

$$\frac{\partial [\epsilon(x, y) \frac{\partial V}{\partial x}]}{\partial x} + \frac{\partial [\epsilon(x, y) \frac{\partial V}{\partial y}]}{\partial y} = -q [n(t, x, y) - n_D(x, y)].$$

WENO-Boltzmann scheme

$$\frac{\partial \Phi}{\partial t} + \frac{\partial}{\partial x}(a_1 \Phi) + \frac{\partial}{\partial y}(a_2 \Phi) + \frac{\partial}{\partial w}(a_3 \Phi) + \frac{\partial}{\partial \mu}(a_4 \Phi) + \frac{\partial}{\partial \phi}(a_5 \Phi) = s(w)C(\Phi)$$

Approximation of derivatives with WENO5

- ▶ Fifth order WENO (*Weighted Essentially Non-Oscillatory*, Shu98) finite difference schemes to approximate the fluxes (WENO5) in x, y, w, μ, ϕ :

$$\frac{\partial}{\partial x}(a_1 \Phi) + \frac{\partial}{\partial y}(a_2 \Phi) + \frac{\partial}{\partial w}(a_3 \Phi) + \frac{\partial}{\partial \mu}(a_4 \Phi) + \frac{\partial}{\partial \phi}(a_5 \Phi)$$

- ▶ Nonoscillatory character near shocks or gradient regions.
 - ▶ Suitable to deal with very strong steep spatial gradients in these devices.
- ▶ Time Integration of $\frac{\partial \Phi}{\partial t}$ with 3rd order TVD (*Total Variation Diminishing*) Runge-Kutta.

WENO-Boltzmann scheme vs. Direct Simulation Monte Carlo (DSMC)

▶ **Advantages with respect DSMC**

1. Suitable to describe almost empty regions of the device.
2. Transient computation
3. Explicit Management of the Probability density function.

- ▶ **Main disadvantage:** Great demands of computational power even in 2D physical space (5 dimensions + time).

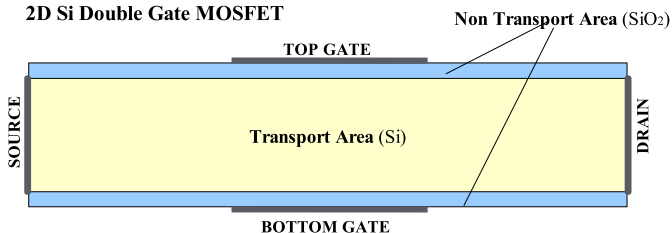
Approach to enable its use

- ▶ Development of flexible and efficient parallel versions of the scheme for parallel architectures.
- ▶ Low cost and widespread architecture: Clusters of SMPs.

Representation of Device information

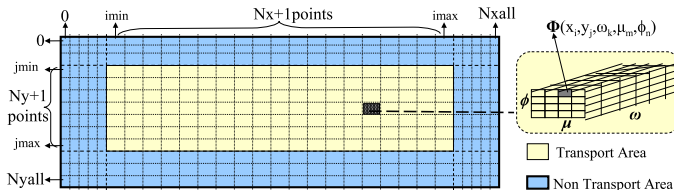
Two areas are considered in the 2D physical space of the device:

- ▶ **Area without charge transport**
- ▶ **Transport area**
 - ▶ $\Phi(t, x, y, w, \mu, \phi)$ is only defined for (x, y) in this area.
 - ▶ The computational work of this area is parallelized



Representation of Device information. Discretization

- ▶ **Transport Area:** 5D uniform grid $(x_i, y_j, w_k, \mu_m, \phi_n)$,
 $i = 0, \dots, N_x, j = 0, \dots, N_y, k = 1, \dots, N_w, m = 1, \dots, N_\mu, n = 1, \dots, N_\phi$.
 - ▶ $\Phi(\mathbf{t}, \mathbf{x}_i, \mathbf{y}_j, \mathbf{w}_k, \mu_m, \phi_n) \implies$ 5D array $\Phi(i, j, k, m, n)$.
 - ▶ $\mathbf{n}(\mathbf{t}, \mathbf{x}_i, \mathbf{y}_j), \mathbf{E}_x(\mathbf{x}_i, \mathbf{y}_j)$ and $\mathbf{E}_y(\mathbf{x}_i, \mathbf{y}_j) \implies$ 2D arrays.
- ▶ **Full spatial device (2D):** $(x_i, y_j), i = 0, \dots, Nxall, j = 0, \dots, Nyall$.
 - ▶ $\mathbf{V}(\mathbf{x}_i, \mathbf{y}_j) \implies$ 2D array $V(i, j)$.



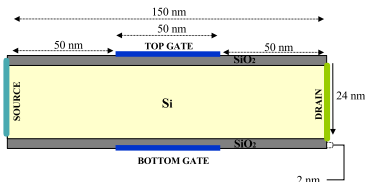
Representation of Device information

Description file for a DG-MOSFET device

```
SET SCALE (centimeter,volt,sec);
GEOMETRY
  XLength = 150.0e-7; YLength = 28.0e-7;
TRANSPORT[(0.0, 2.0e-7)->(150.0e-7, 26.0e-7)];
SOURCE [(0.0, 2.0e-7)->(0.0, 26.0e-7)];
DRAIN [(150.0e-7, 2.0e-7)->(150.0e-7, 26.0e-7)];
GATE [(50.0e-7, 0.0)->(100.0e-7, 0.0)];
GATE [(50.0e-7, 28.0e-7)->(100.0e-7, 28.0e-7)];
Nxall=30; Nyall=56; Nx=30; Ny=48; Nw=120; Nmu=12;
  Nphi=12; NMULT =2;
END
DOPING
  FILE ("doping.dat");
END
POTENTIAL
  SOURCE=0.0;
  DRAIN =0.5;
  GATE[0]=1.0;
  GATE[1]=1.0;
END
DIELECTRIC
  REGION [ (0.0, 0.0)->(15.0e-6, 2.0) ] =3.9;
  REGION [ (0.0, 26.0e-7)->(150.0e-7, 28.0e-7) ]= 3.9;
  REGION [ (0.0, 2.0e-7)->(150.0e-7, 26.0e-7) ]=11.9;
END
SIMULATION
  TEND =3.5; NTOT =9999999; CFL =0.9;
END
```

doping.dat

0	2e-07	1.0e+20
5e-07	2e-07	1.0e+20
1e-06	2e-07	1.0e+20
1.5e-06	2e-07	1.0e+20
2e-06	2e-07	1.0e+20
2.5e-06	2e-07	1.0e+20
3e-06	2e-07	1.0e+20
3.5e-06	2e-07	1.0e+20
...		



$$\left[\frac{\partial \Phi}{\partial t} \right]_{i,j,k,m,n} = L(\Phi)(i, k, k, m, n) = [s(w)C(\Phi)]_{i,j,k,m,n} - \left[\frac{\partial}{\partial x} (a_1 \Phi) + \dots + \frac{\partial}{\partial \phi} (a_5 \Phi) \right]$$

Time integration of $\Phi(i, j, k, m, n)$: 3rd order TVD RK method

- ▶ Φ^n (in t^n) \rightarrow Φ^{n+1} (in $t^{n+1} = t^n + \Delta t$)
- ▶ 3 stages

$$\Phi^n = \Phi^{(0)} \xrightarrow{\text{stage } 0} \Phi^{(1)} \xrightarrow{\text{stage } 1} \Phi^{(2)} \xrightarrow{\text{stage } 2} \Phi^{(3)} = \Phi^{n+1}$$

- ▶ In s -th stage, $L(\Phi^{(s)})(i, k, k, m, n)$ must be evaluated.

Computation of $C(\Phi)_{i,j,k,m,n}$ and $n(i, j)$

- ▶ Composite mid-point rule to approximate the integrals

Computation of spatial derivatives in $L(\Phi)_{i,j,k,m,n}$

Dimension by dimension approximation to the spatial derivatives using WENO5 : **Most costly computing phase**

- ▶ **Example:** WENO5 to approximate $\frac{\partial}{\partial x}(a_1 \Phi)$ in $(x_i, y_j, w_k, \mu_m, \phi_n)$

$$\frac{\partial}{\partial x} a_1 \Phi(i, j, k, m, n) = \begin{cases} W(g_{i-3}, \dots, g_{i+2}), & \text{si } a_1 > 0 \\ W(g_{i+3}, \dots, g_{i-2}), & \text{si } a_1 \leq 0 \end{cases}$$

$$g_i = a_1 \Phi(i, j, k, m, n), \quad i = -3, \dots, N_x + 3,$$

- ▶ **Variable 6-point asymmetric stencil.**

Numerical Schemes in Full Spatial Device

Computation of Electric Potential $V(i, j)$

Numerical solution of 2D Poisson Eq. \rightarrow Linear system

$$A_{n \times n} \cdot V = -q [n(i, j) - n_D(i, j)]$$

- $n = (Nx_{all} + 1)(Ny_{all} + 1)$, $Nx_{all} < 300$ and $Ny_{all} < 300$.
- A is a **constant** banded matrix with bandwidth $2Nx_{all} + 3$.
- One initial Banded LU factorization.
- One Forward elimination and back substitution is made for each Runge-Kutta stage

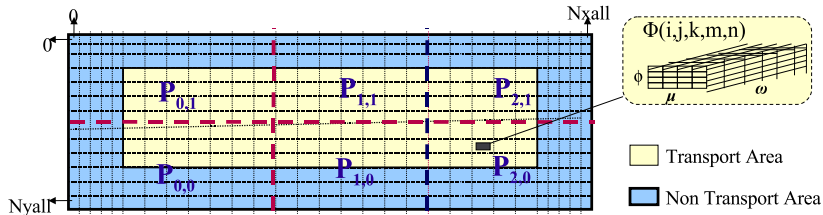
Computation of Electric field $E_x(i, j)$ and $E_y(i, j)$

$$E_x(i, j) = \frac{V(i+1, j) - V(i-1, j)}{x_{i+1} - x_{i-1}}, \quad E_y(i, j) = \frac{V(i, j+1) - V(i, j-1)}{y_{i+1} - y_{i-1}}$$

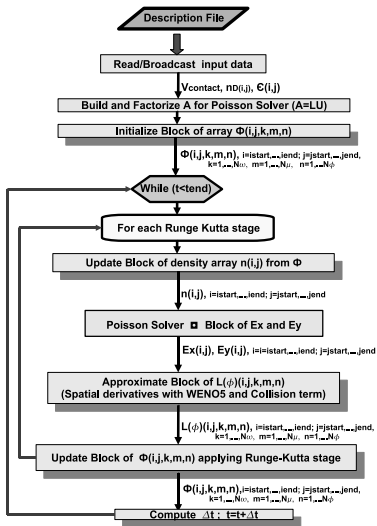
Parallel Algorithm. Decomposition Strategy

- ▶ $\Phi(i, j, k, m, n)$ is block distributed onto a 2D proc. grid by splitting (x_i, y_j)
- ▶ A similar distribution for 2D arrays in transport area
- ▶ Workload balance centred on transport area
- ▶ Satisfactory load balance, low communication costs and high reuse.

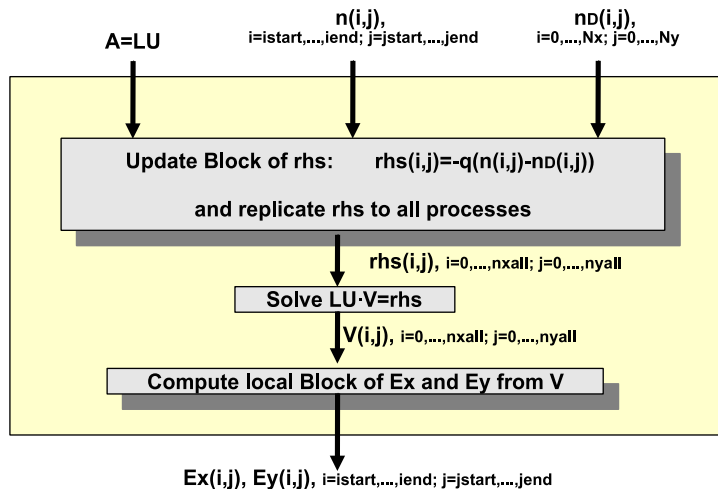
P=6 procs. , Nx=18, Ny=6 \Rightarrow 3 \times 2 processor grid



Parallel Algorithm. General View of a process



Parallel Algorithm. Poisson Solver



Parallel Algorithm. Compute Block of $L(\Phi)(i, j, k, m, n)$

Input: $n(i, j)$, $E_x(i, j)$, $E_y(i, j)$, $\Phi(i, j, k, m, n)$,
 $i = istart, \dots, iend$; $j = jstart, \dots, jend$;
 $k = 1, \dots, N_w$, $m = 1, \dots, N_\mu$, $n = 1, \dots, N_\phi$.

1. $L(i, j, k, m, n) = s(w_k, \mu_m)C(i, j, k, m, n)$

2. $L(i, j, k, m, n) - = \left(\frac{\partial}{\partial w} (a_3 \Phi) + \frac{\partial}{\partial \mu} (a_4 \Phi) + \frac{\partial}{\partial \phi} (a_5 \Phi) \right)_{i,j,k,m,n}$

3. Exchange Φ boundaries in x direction

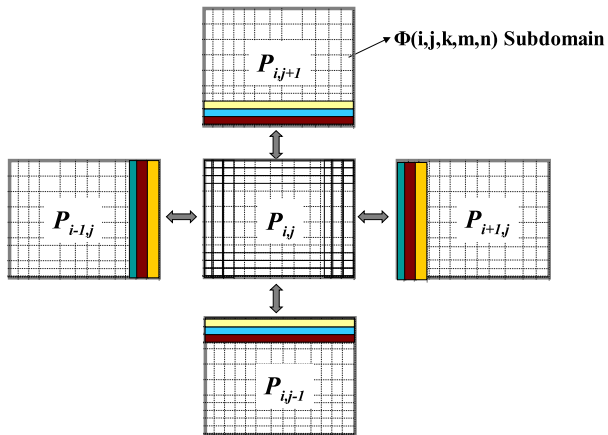
$$L(i, j, k, m, n) - = \frac{\partial}{\partial x} (a_1 \Phi)_{i,j,k,m,n}$$

4. Exchange Φ boundaries in y direction

$$L(i, j, k, m, n) - = \frac{\partial}{\partial y} (a_2 \Phi)_{i,j,k,m,n}$$

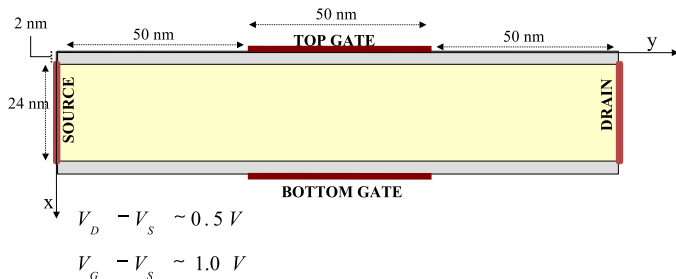
Parallel Algorithm. Communication pattern for WENO5

- ▶ Only the fluxes in x and y require interprocessor communication.
- ▶ A 7 point symmetric stencil is assumed to apply WENO5.

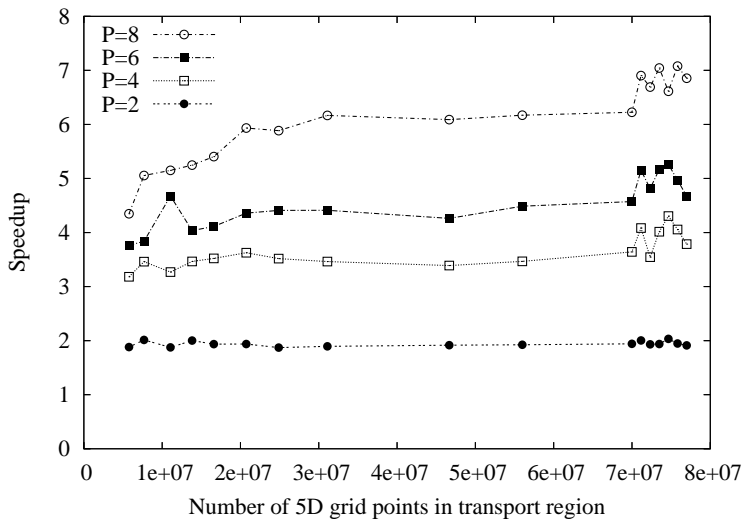


Experimental results

- ▶ Spatial grid for full device: $(N_{xall}, N_{yall}) = (30, 56)$.
- ▶ 5D grid for transport area: $(N_x, N_y, N_w, N_\mu, N_\phi) = (30, 48, 120, 12, 12)$.
- ▶ Cluster of 4 dual AMD Opteron 2.4 MHz via Gigabit Ethernet.
- ▶ C++ code + mpich + ACML Lapack
- ▶ Time integration from $0ps$ through $3.5ps$.



Experimental results. Parallel speedup



- ▶ Development of a **quantum-deterministic model** for DG-MOSFET devices and integration in the parallel simulator.
- ▶ **Use of GPUs** to speedup the numerical simulation on CPU-GPU clusters.
- ▶ **Non Uniform Grids**: WENO with interpolation at subdomain interfaces (*Sebastian-Shu 2003*).
- ▶ Dynamic Load balancing strategy to exploit efficiently heterogeneous systems.

**GRACIAS POR VUESTRA
ATENCIÓN**

Experimental results. Execution times

